

# Examiner Notes or Reply Brief

## (9) Prior Art of Record.

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The below listed prior art are presented only for their evidentiary value to illustrate the state of the art at the time the invention was made in response to Applicant's general challenge to Examiner's Official Notice of said state of the art.

<u>PATENT NUMBER</u>	<u>INVENTOR</u>	<u>PATENT DATE</u>
5,304,846	Azar <i>et al.</i>	19 April 1994
5,633,800	Bankert <i>et al.</i>	27 May 1997
JP 4-12559A	Fujitsu Ltd.	17 January 1992
JP 8-125369	NEC Corp.	17 May 1996

## (11) Grounds of Rejection.

(No changes of any kind have been made to the rejections found in the original Examiner's Answer)

## (12) Response to Argument.

Applicant's arguments have been previously addressed and it is believed that the record stands ready for upholding the instant rejections without need for further response with the exception that Applicant has made a general challenge to Examiner's statements of Official Notice to the state of the art in electronics cooling and machine monitoring.

The Examiner notes that Azar *et al.* discloses that cooling fin dimensions and specifically cooling fin thickness values should be modified to obtain the desired cooling effects (fin length and thickness, see abstract and figure 1). The Examiner would particularly note figure 16 wherein as proposed by the Examiner in the rejection construct, the electronics are placed above their respective cooling fins.

The Examiner notes that Bankert *et al.* discloses that rotating machinery is commonly monitored for proper function.

The Examiner notes that Fujitsu, Ltd. discloses that cooling fins may be of varying lengths (see English abstract).

The Examiner notes that NEC Corporation discloses that cooling fins may be of curved configurations (see English abstract, figures 1 and 2).

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